## **APPENDIX OF PENDING CLAIMS**

- 1. A semiconductor-based device processing apparatus comprising:
  - a chuck for supporting a wafer; and
- a barrier having a first position relative to the wafer wherein the first position relative to the wafer substantially facilitates etch uniformity for a chemically driven etch process, and having a second position relative to the wafer wherein the second position relative to the wafer does not interfere with the etch uniformity of an ion driven etch process.
- 2. The apparatus as recited in claim 1 wherein the barrier is moved to establish the first and the second position of the barrier relative to the wafer.
- 3. The apparatus as recited in claim 2 wherein the first position is substantially above the wafer and the second position is substantially below the wafer.
- 4. The apparatus as recited in claim 1 wherein the chuck is moved to establish the first and the second position of the barrier relative to the wafer.
- 5. The apparatus as recited in claim 1 wherein the barrier surrounds the periphery of the wafer.
- 6. The apparatus as recited in claim 1 wherein the barrier is moved between the first and the second position using an actuator.
- 7. The apparatus as recited in claim 1 wherein the barrier has a third position.
- 8. A plasma processing apparatus comprising:
  - a chuck for supporting a wafer; and
- a moveable barrier having a first position and a second position, wherein the first position is capable of restricting diffusion of gases over the wafer within the plasma processing apparatus to the wafer.
- 9. The apparatus as recited in claim 8 wherein the plasma processing apparatus further comprises an actuator operable to move the moveable barrier between the first position and the second position.
- 10. (Once Amended) The apparatus as recited in claim 8 wherein at least a portion of the moveable barrier is within 1/8 inches to 2 inches of the wafer when in the first position.
- 11. The apparatus as recited in claim 8 wherein the moveable barrier includes an opening.
- 12. The apparatus as recited in claim 8 wherein the moveable barrier shape is relative to the shape of the wafer.
- 13. The apparatus as recited in claim 12 wherein the moveable barrier shape is substantially circular.